

## ZXTC2062E6 20V, SOT23-6, complementary medium power transistors

#### Summary

$$\begin{split} &\mathsf{BV}_{\mathsf{CEO}} > 20 \; (\text{-}20)\mathsf{V} \\ &\mathsf{BV}_{\mathsf{ECO}} > 5 \; (\text{-}4)\mathsf{V} \\ &\mathsf{I}_{\mathsf{C(cont)}} = 4 \; (\text{-}3.5)\mathsf{A} \\ &\mathsf{V}_{\mathsf{CE(sat)}} < 50 \; (\text{-}65)\mathsf{mV} @ \; \mathsf{1A} \\ &\mathsf{R}_{\mathsf{CE(sat)}} = 35 \; (\mathsf{54})\mathsf{m}\Omega \\ &\mathsf{P}_{\mathsf{D}} = 1.1\mathsf{W} \end{split}$$

## Description

Advanced process capability has been used to achieve this high performance device. Combining NPN and PNP transistors in the SOT23-6 package provides a compact solution for the intended applications

### Features

- NPN-PNP combination
- Very low saturation voltage
- High gain
- SOT23-6 package

### Applications

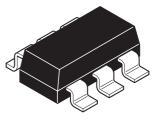
- MOSFET and IGBT gate driving
- Motor drive

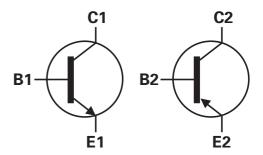
### Ordering information

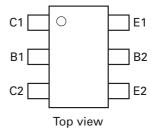
DEVICE	Reel size	Tape width	Quantity	
	(inches)	(mm)	per reel	
ZXTC2062E6TA	7	8	3000	

### **Device marking**

2062







### Absolute maximum and thermal ratings

PARAMETER	Symbol	Limit	Unit
Collector-base voltage	V <sub>CBO</sub>	100(-25)	V
Collector-emitter voltage	V <sub>CEO</sub>	(-)20	V
Emitter-collector voltage (reverse blocking)	V <sub>ECO</sub>	5(-4)	V
Emitter-base voltage	V <sub>EBO</sub>	(-)7	V
Continuous collector current <sup>(c)(f)</sup>	۱ <sub>C</sub>	4(-3.5)	А
Peak pulse current	I <sub>CM</sub>	(-)10	А
Base current	ا <sub>B</sub>	(-)1	А
Power dissipation at $T_A = 25^{\circ}C^{(a)(f)}$	PD	0.7	W
Linear derating factor		5.6	mW/°C
Power dissipation at $T_A = 25^{\circ}C^{(b)(f)}$	PD	0.9	W
Linear derating factor		7.2	mW/°C
Power dissipation at $T_A = 25^{\circ}C^{(b)(g)}$	P <sub>D</sub>	1.1	W
Linear derating factor		8.8	mW/°C
Power dissipation at $T_A = 25^{\circ}C^{(c)(f)}$	PD	1.1	W
Linear derating factor		8.8	mW/°C
Power dissipation at $T_A = 25^{\circ}C^{(d)(f)}$	PD	1.7	W
Linear derating factor		13.6	mW/°C
Operating and storage temperature range	T <sub>j</sub> , T <sub>stg</sub>	-55 to +150	°C
Thermal resistance junction to ambient <sup>(a)(f)</sup>	R <sub>θJA</sub>	179	°C/W
Thermal resistance junction to ambient <sup>(b)(f)</sup>	R <sub>θJA</sub>	139	°C/W
Thermal resistance junction to ambient <sup>(b)(g)</sup>	R <sub>θJA</sub>	113	°C/W
Thermal resistance junction to ambient <sup>(c)(f)</sup>	R <sub>θJA</sub>	113	°C/W
Thermal resistance junction to ambient <sup>(d)(f)</sup>	R <sub>θJA</sub>	73	°C/W

#### NOTES:

- (a) For a device surface mounted on 15mm x 15mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.
- (b) For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.
- (c) For a device surface mounted on 50mm x 50mm x 1.6mm FR4 PCB with high coverage of single sided 2oz copper, in still air conditions.

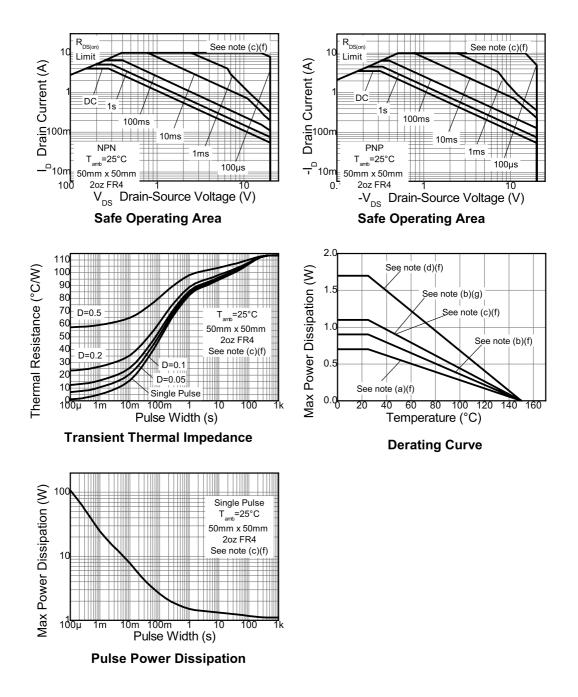
(d) As above measured at t<5 seconds.

(e) Repetitive rating - pulse width limited by maximum junction temperature. Refer to Transient Thermal Impedance graph.

(f) For device with one active die, both collectors attached to a common sink.

(g) For device with two active dice running at equal power, split sink 50% to each collector.

### **Thermal characteristics**



## **ELECTRICAL CHARACTERISTICS (at Tamb = 25°C unless otherwise stated).**

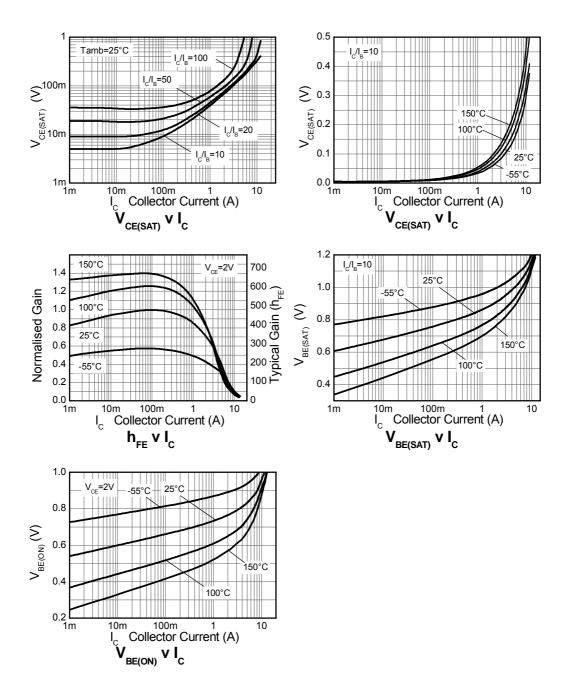
Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
		100(-25)	140(-55)		V	I <sub>C</sub> = (-)100μA
Collector-emitter	BV <sub>CEO</sub>	(-)20	35(-45)		V	I <sub>C</sub> = (-)10mA <sup>(*)</sup>
breakdown voltage						
(base open)						
Emitter-base	BV <sub>EBO</sub>	(-)7	(-)8.3		V	I <sub>E</sub> = (-)100 A
breakdown voltage						
Emitter-collector	BV <sub>ECO</sub>	5(-4)	6(-8.5)		V	I <sub>E</sub> = (-)100 A
breakdown voltage						
(base open)				()=0		
Collector-base cut-off	I <sub>СВО</sub>		<1	(-)50	nA	$V_{CB} = 100(-25)V$
current				(-)0.5	Α	V <sub>CB</sub> =100(-25)V, T <sub>amb</sub> = 100°C
Emitter-base cut-off	I <sub>EBO</sub>		<1	(-)50	nA	V <sub>EB</sub> = (-)5.6V
current						
Collector-emitter	V <sub>CE(sat)</sub>		40(-55)	50(-65)	mV	$I_{C} = (-)1A, I_{B} = (-)100mA^{(*)}$
saturation voltage			60(-100)	75(-135)	mV	$I_{C} = (-)1A, I_{B} = (-)20mA^{(*)}$
			95(-185)	115(-280)	mV	$I_{C} = (-)2A, I_{B} = (-)40mA^{(*)}$
			(-190)	(-250)	mV	(I <sub>C</sub> = -3.5A, I <sub>B</sub> = -175mA) <sup>(*)</sup>
			140	190	mV	$I_{C} = 4A, I_{B} = 200 mA^{(*)}$
Base-emitter	V <sub>BE(sat)</sub>		(-925)	(-1000)	mV	(I <sub>C</sub> = -3.5A, I <sub>B</sub> = -175mA <sup>(*)</sup> )
saturation voltage			940	1050	mV	$I_{C} = 4A, I_{B} = 200 \text{mA}^{(*)}$
Base-emitter turn-on	V <sub>BE(on)</sub>		(-835)	(-900)	mV	$(I_{C} = -3.5A, V_{CE} = -2V^{(*)})$
voltage			810	900	mV	$I_{C} = 4A, V_{CE} = 2V^{(*)}$
Static forward current	h <sub>FE</sub>	300(300)	450(450)	900(900)		$I_{C} = (-)10mA, V_{CE} = (-)2V^{(*)}$
transfer ratio		280(170)	420(300)			$I_{\rm C} = (-)1A, V_{\rm CE} = (-)2V^{(*)}$
		(65)	(100)			$(I_{\rm C} = -3.5 {\rm A}, V_{\rm CF} = -2 {\rm V}^{(*)})$
		140	210			$I_{C} = 4A, V_{CE} = 2V^{(*)}$
			(15)			$(I_{\rm C} = -10A, V_{\rm CF} = -2V^{(*)})$
			15			$I_{C} = 15A, V_{CE} = 2V^{(*)}$
Transition frequency	f <sub>T</sub>		215		MHz	I <sub>C</sub> = (-)50mA, V <sub>CE</sub> = (-)10V
			(290)			f = 100MHz
Output capacitance	C <sub>OBO</sub>		17(21)	25(30)	pF	V <sub>CB</sub> = (-)10V, f = 1MHz <sup>(*)</sup>
Delay time	t <sub>d</sub>		68(56)		ns	
Rise time	t <sub>r</sub>		72(68)		ns	$V_{CC} = (-)10V. I_{C} = (-)1A,$
Storage time	t <sub>s</sub>		361(158)		ns	I <sub>B1</sub> = -I <sub>B2</sub> = (-)10mA.
Fall time	t <sub>f</sub>		64(59)		ns	

#### NOTES:

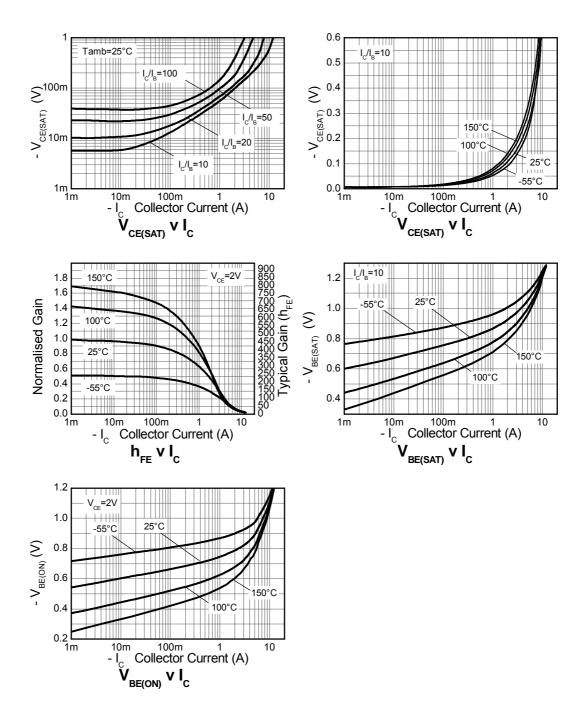
(\*) Measured under pulsed conditions. Pulse width  $\leq 300 \mu s;$  duty cycle  $\leq 2\%.$ 

( ) = PNP

## **NPN electrical characteristics**

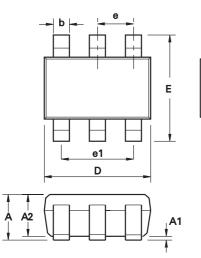


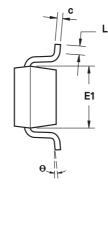
### **PNP electrical characteristics**



## Package outline SOT23-6

## Package outline





## 

Pad latout details

DIM	Millin	neters	Inches		
	Min.	Max.	Min.	Max.	
А	0.90	1.45	0.354	0.0570	
A1	0.00	0.15	0.00	0.0059	
A2	0.90	1.30	0.0354	0.0511	
b	0.35	0.50	0.0078	0.0196	
С	0.09	0.26	0.0035	0.0102	
D	2.70	3.10	0.1062	0.1220	
E	2.20	3.20	0.0866	0.1181	
E1	1.30	1.80	0.0511	0.0708	
L	0.10	0.60	0.0039	0.0236	
е	0.95	REF	0.037	4 REF	
e1	1.90	REF	0.074	8 REF	
L	0°	30°	0°	30°	

Note: Controlling dimensions are in millimeters. Approximate dimensions are provided in inches

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